

IPC-4553A

Specification for Immersion Silver Plating for Printed Boards

Developed by the Plating Processes Subcommittee (4-14) of the Fabrication Processes Committee (4-10) of IPC

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Users of this publication are encouraged to participate in the development of future revisions.

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Table of Contents

1 SC	OPE		1		Figures
1.1		nt of Scope		Figure 3-1	Example of Uniform Plating
1.2		ion		Figure 3-2	Example of Staining of the Silver
1.3		re		Figure 3-3	Another Example of Surface Staining
1.4 1.4.1		ance Functions		Figure 3-4	Additional Staining Example
		oility		Figure 3-5	Additional Staining Example
1.4.2 1.4.2.1		Surfacene Switches		Figure 3-6	IPC-2221 Test Speciman M, Surface Mount Solderability Testing, mm [in]
1.4.2.2 1.4.3		Dome Contacts		Figure 3-7	Improper Packing or Storage Can Result in the Immersion Silver Corroding
		· ·		Figure A-4-1	Immersion Silver Industry Survey Results 1
1.4.4 2 AF		Im Wire Bonding LE DOCUMENTS		Figure A-4-2	Comparison of Thin Versus Thick Silver Solderability Performance Using Real
2.1					Time Shelf Life
2.2		ndards		Figure A-4-3	XRF Results of Thin IAg Deposit 12
		a TM		Figure A-4-4	XRF Results of Thick IAg Deposit 13
2.3	Telcordi	a ^{1M}	2	Figure A-4-5	Wetting Balance Coupon
3 RE		IENTS		Figure A-4-6	Supplied Immersion Silver Deposit for Wetting Balance Testing
3.2	Finish T	hickness	2	Figure A-4-7	Solderability Performance Vendor A - Real Time Storage
3.2.1 3.3		on Silver (IAg) Thickness		Figure A-4-8	Solderability Performance Vendor D - Real Time Storage
3.4	Adhesio	n	2	Figure A-4-9	Solderability Performance Vendor E - Real Time Storage
3.5 3.6	Cleanlin	ess	4	Figure A-4-10	Comparison of Vendor D Protected vs Unprotected - Day 709
3.7 3.8		ytic Corrosion Testingand Storage		Figure A-4-11	Comparison of Vendor A Protected vs Unprotected - Day 763
3.9 3.10	Chemica	al Resistanceequency Signal Loss	6	Figure A-4-12	Comparison of Vendor E Protected vs Unprotected - Day 709
3.11	Microvo	ids	6	Figure A-4-13	IAg Deposit Thickness for TM-650, 2.6.14.1, as Measured by "Micron X" XRF Unit
	Qualification Sample	ation Test Coupons nce Tests	6 6	Figure A-4-14	Final Readings in Chamber of First Round of Electrolytic Corrosion Testing at 35°C/92% R.H., Post 500 Hours of 10 Volt DC Bias. NO FAILURES PRODUCED
4.3	Quality	Conformance Testing	6	Figure A-4-15	SEM Image of Vendor A's 3X Sample Confirming XRF Measurements
APPEN APPEN		Chemical Definitions Process Sequence (Generic)		Figure A-4-16	Final Readings in Chamber of First Round of Electrolytic Corrosion Testing at 65°C/87% R.H., Post 500 Hours of 10 Volt DC Bias - NO FAILURES
APPEN	IDIX 3	Qualification of IAg Process by the Board Supplier	9	Figure A-4-17	PRODUCED
APPENDIX 4		Standard Developments Efforts of Immersion Silver		i igui o A-4-17	65°C / 87% R.H. with 10 Volt Bias Applied - No Failures for Dendritic
APPENDIX 5		X-Ray Fluorescence (XRF) Spectroscopy			Growth but Water Spotting Clearly Evident
APPEN	IDIX 6	ROUND ROBIN TESTING		Figure A-4-18	Test Protocol Applied Voltages Used for 3-11G Testing

IPC-4553A May 2009

Figure A-4-19	Comb Test Pattern and UL Parallel Pattern Used for Testing	21
Figure A-4-20	SIR Values for the Test at 96 Hours - 35°C/87.5% R.H. All Five IAg Suppliers' Data are Combined	21
Figure A-4-21	Resistance Values at 596 Hours - All Groups Included - Different Spaces/ Bias Voltages	22
Figure A-4-22	Resistance Readings at 1344 Hours for IAg as a Function of Applied Volts/mil	22
Figure A-4-23	Evidence of Dendritic Growth on the Electrolytic Silver Sample	23
Figure A-4-24	SEM/EDX Analysis of Figure 14, Above	23
Figure A-4-25	Contact Resistance for IAg Supplier A	24

Tables

Table 3-1	Requirements of IAg	3
Table 4-1	Qualification Test Coupons	6
Table A-6-1	Plating Thicknesses on Test Vehicles	
	[µinches]	28

May 2009 IPC-4553A

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1 SCOPE

- **1.1 Statement of Scope** This specification sets the requirements for the use of Immersion Silver (IAg) as a surface finish for printed boards. This specification is intended to set requirements for IAg deposit thickness based on performance criteria. It is intended for use by chemical supplier, printed board manufacturer, electronics manufacturing services (EMS) and original equipment manufacturer (OEM).
- **1.2 Description** IAg is a thin immersion deposit over copper. It is a multifunctional surface finish, applicable to soldering. It may also be applicable for some press fit connections and as a contact surface. It has the potential to be suitable for aluminum wire bonding. The immersion silver protects the underlying copper from oxidation over its intended shelf life. Exposure to moisture and air contaminants, such as sulfur and chlorine, may negatively impact the useful life of the deposit. The impact can range from a slight discoloration of the deposit to the pads turning completely black. Proper packaging is a requirement.
- **1.3 Objective** This specification sets the requirements specific to IAg as a surface finish. As other finishes require specifications, they will be addressed by the IPC Plating Processes Subcommittee as part of the IPC-4550 specification family. As this and other applicable specifications are under continuous review, the subcommittee will add appropriate amendments and make necessary revisions to these documents.

1.4 Performance Functions

- **1.4.1 Solderability** This primary function of IAg is to provide a solderable surface finish, suitable for all surface mount and through-hole assembly applications and with an appropriate shelf life. The deposit has demonstrated the ability to meet a shelf life of 12 months per IPC J-STD-003 and industry data, when handled per this specification's requirements.
- **1.4.2 Contact Surface** There is a possibility for using IAg for the following applications. The use of Immersion Silver is acceptable for the IPC-6010 series Class 1 and Class 2 applications, but is NOT currently recommended for the IPC-6010 series Class 3 applications which are for High Reliability Electronic Products where equipment

downtime cannot be tolerated, and the circuitry **shall** function, when required. Examples of such Class 3 applications are for life support items and critical weapons systems.

- **1.4.2.1 Membrane Switches** The IAg surface with as little as $0.1 \mu m$ [4 μin] of immersion silver has demonstrated that it is suitable for one million actuations with negligible resistance change. However the end use atmosphere (temperature/humidity/contaminants) may degrade this performance. The end user **shall** determine the impact of use environments on the IAg deposit.
- **1.4.2.2 Metallic Dome Contacts** Data on this topic should be submitted to the IPC 4-14 Plating Processes Subcommittee to be considered for inclusion in upcoming revisions of this standard.
- **1.4.3 EMI Shielding** IAg is one of the surface finishes that may be used as an interface between electromagnetic interference (EMI) shielding and the printed board. A key characteristic for this application is a consistent metal interface between the printed board metallization and the shield material. The formation of a highly conductive interface between the two surfaces will ensure excellent EMI shielding capability, which should also provide resistance to atmospheric influences on the IAg deposit. The end user **shall** determine the impact of the end use environment on the reliability of the shield interface. Tarnish of surrounding areas not in contact directly with the shield is NOT a reason to reject the printed board/deposit but rather an indication of the impact of the atmosphere on an active metal.
- **1.4.4 Aluminum Wire Bonding** IAg meets the requirements of MIL-STD-883, Method 2011.7. Variables that affect performance include cleanliness, substrate materials, wire thickness and surface topography. IAg is not a surface leveler; the surface topography largely depends on the conditions of the underlying copper surface. While producing acceptable wire bonds, silver, unlike the other Noble metals used for this application, is potentially not stable due to its reactive nature with the atmosphere in which it exists. Total encapsulation of the wire bonded sites is recommended in order to ensure consistent and reliable long term bonds. The committee is actively seeking additional data on the use of immersion silver as a suitable wire bonding metallization.